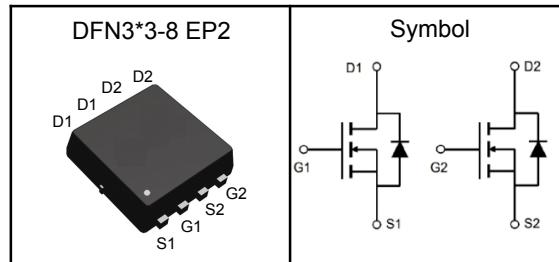


Dual N-Channel Enhancement Mode MOSFET

Features

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant
- 100% Avalanche Tested

Pin Description



Applications

- Power Management in Desktop Computer
- DC/DC Converters

V_{DSS}	40	V
$R_{DS(ON)-Typ}$	14	$m\Omega$
I_D	7.8	A

Absolute Maximum Ratings ($T_C=25^\circ C$, Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V_{DSS}	Drain-Source Voltage	40	V
V_{GSS}	Gate-Source Voltage	± 20	V
T_J	Maximum Junction Temperature	-55 to 150	$^\circ C$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
$I_{DM}^{①}$	Pulse Drain Current Tested $T_A=25^\circ C$	19	A
I_D	Continuous Drain Current	7.8	A
P_D	Maximum Power Dissipation $T_A=25^\circ C$	1.31	W
E_{AS}	Avalanche Energy, Single pulse $L=0.1mH$	20	mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	96	$^\circ C/W$

Note ① : Max. current is limited by bonding wire.

Note ② : UIS tested and pulse width are limited by maximum junction temperature $150^\circ C$.

Note ③ : Surface Mounted on $1in^2$ FR-4 board with 1oz.

Dual N-Channel Enhancement Mode MOSFET

Electrical Characteristics ($T_J=25^\circ\text{C}$, Unless Otherwise Noted)

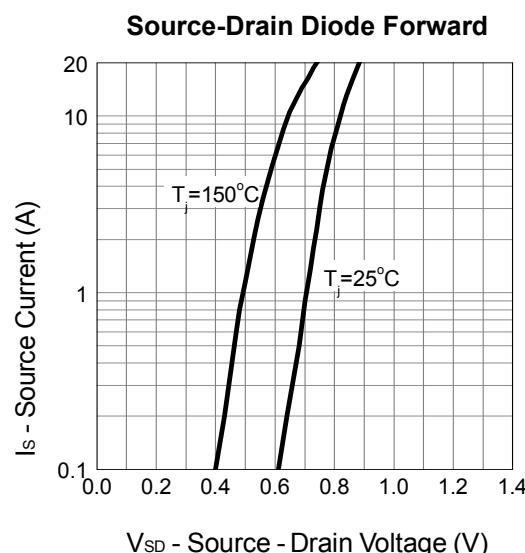
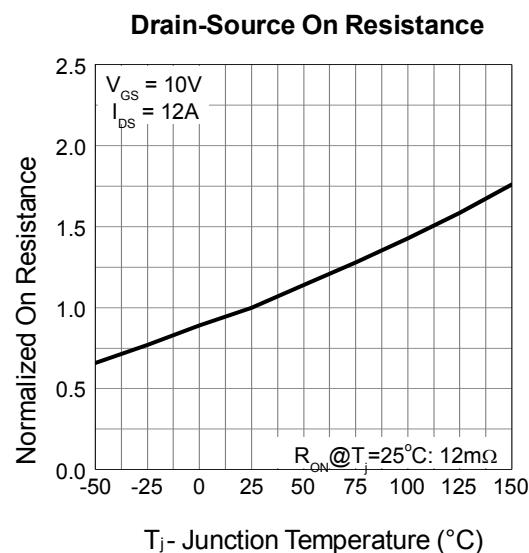
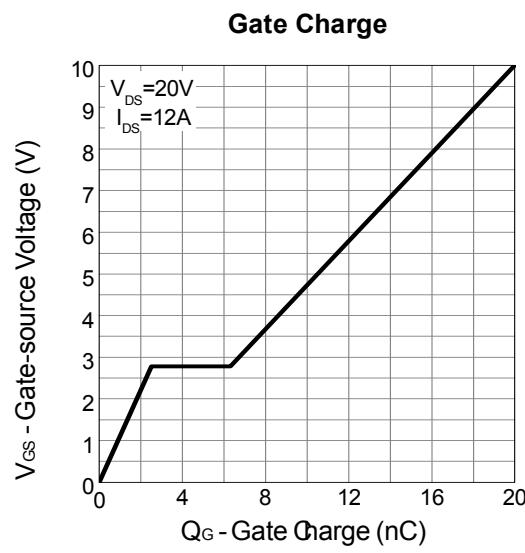
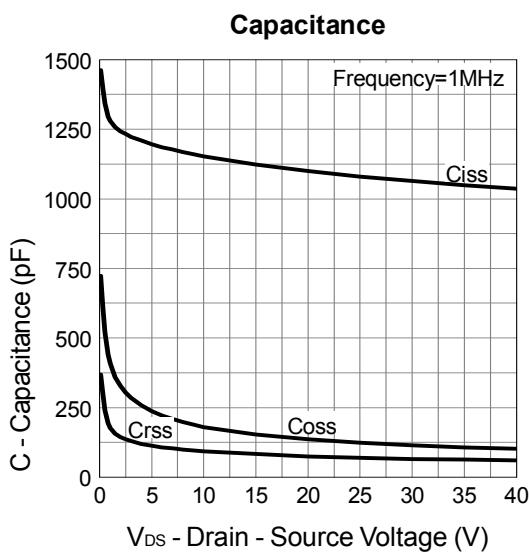
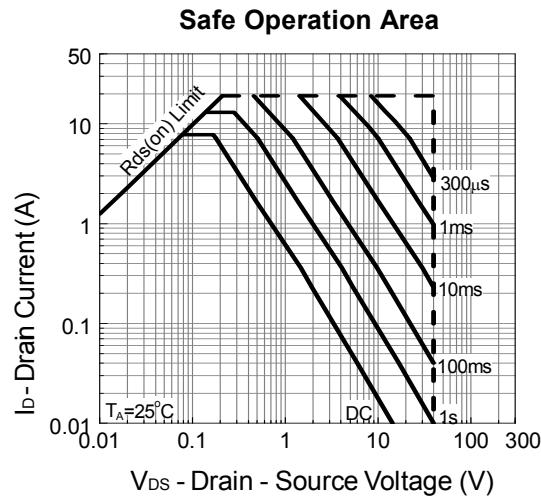
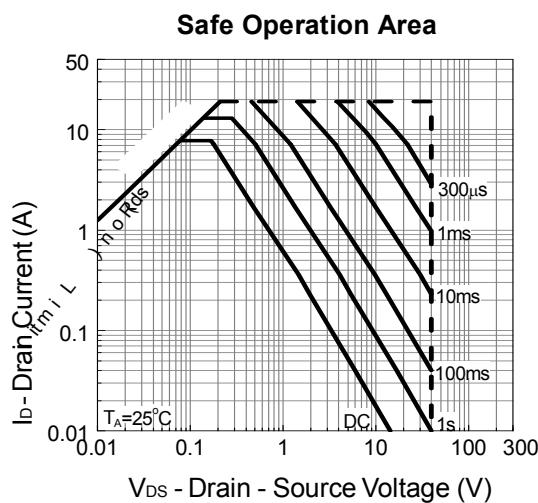
Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
Static Electrical Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	40	---	---	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=32\text{V}$, $V_{\text{GS}}=0\text{V}$	---	---	1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_D=250\mu\text{A}$	1.5	---	2.5	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
$R_{\text{DS(ON)}}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}$, $I_D=12\text{A}$	---	14	17	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_D=10\text{A}$	---	17	20	$\text{m}\Omega$
Dynamic Characteristics^⑤						
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$, $V_{\text{DS}}=20\text{V}$, Freq.=1MHz	---	1095	---	pF
C_{oss}	Output Capacitance		---	135	---	
C_{rss}	Reverse Transfer Capacitance		---	74	---	
$T_{\text{d(on)}}$	Turn-on Delay Time	$V_{\text{DD}}=30\text{V}$, $R_L=30\Omega$, $I_{\text{DS}}=1\text{A}$, $V_{\text{GEN}}=10\text{V}$, $R_G=6\Omega$	---	8.2	---	nS
T_r	Turn-on Rise Time		---	6.8	---	
$T_{\text{d(off)}}$	Turn-off Delay Time		---	25.2	---	
T_f	Turn-off Fall Time		---	6.4	---	
Q_g	Total Gate Charge	$V_{\text{DS}}=20\text{V}$, $V_{\text{GS}}=4.5\text{V}$, $I_D=12\text{A}$	---	9.6	---	nC
Q_{gs}	Gate-Source Charge		---	2.5	---	
Q_{gd}	Gate-Drain Charge		---	3.8	---	
Source-Drain Characteristics						
V_{SD}	Diode Forward Voltage	$I_S=10\text{A}$, $V_{\text{GS}}=0\text{V}$	---	0.88	1.1	V
t_{rr}	Reverse Recovery Time	$I_F=12\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$, $T_J=25^\circ\text{C}$, $V_{\text{DS}}=20\text{V}$	---	17	---	nS
Q_{rr}	Reverse Recovery Charge		---	12	---	nC

Note ④: Pulse test (pulse width $\leq 300\text{us}$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

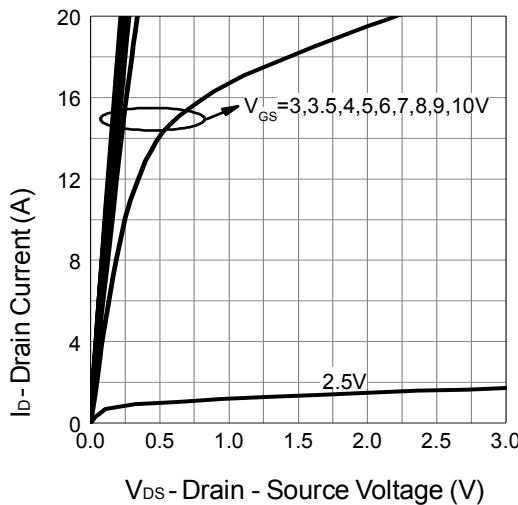
Dual N-Channel Enhancement Mode MOSFET

Typical Characteristics

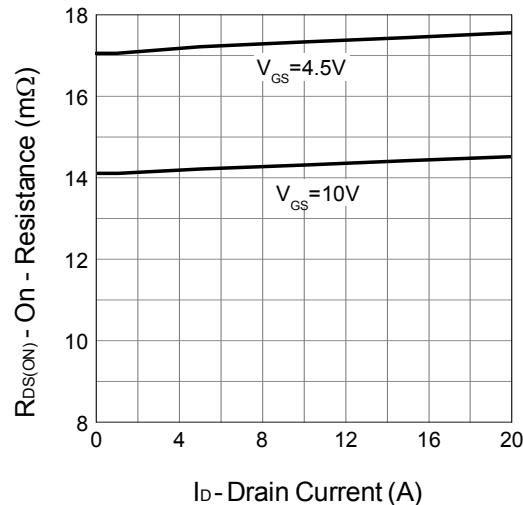


Dual N-Channel Enhancement Mode MOSFET

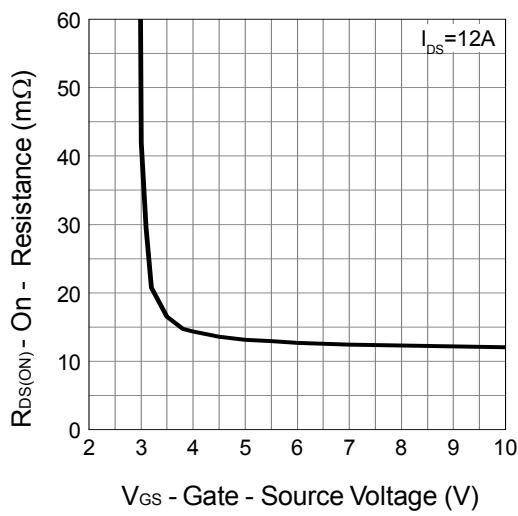
Output Characteristics



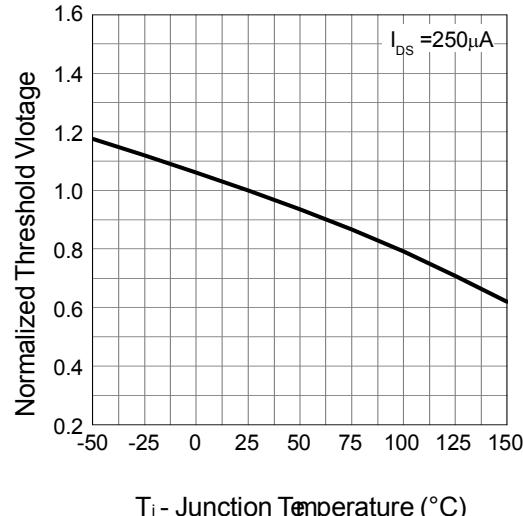
Drain-Source On Resistance



Gate-Source On Resistance

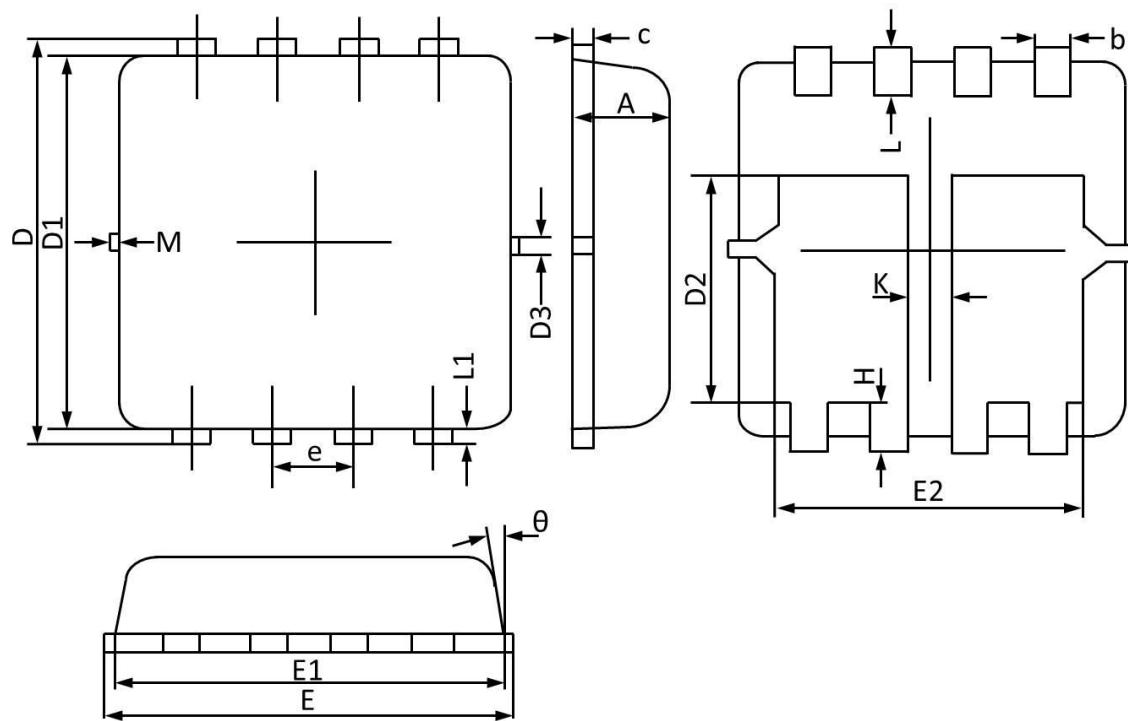


Gate Threshold Voltage



Dual N-Channel Enhancement Mode MOSFET

DFN3*3-8 EP2 Package Outline Data



Symbol	Dimensions (unit:mm)			Symbol	Dimensions (unit:mm)		
	Min	Typ	Max		Min	Typ	Max
A	0.70	0.75	0.85	E2	2.35	2.50	2.60
b	0.25	0.30	0.35	e	0.65 BSC		
c	0.10	0.17	0.25	H	0.30	0.40	0.50
D	3.10	3.30	3.45	L	0.30	0.40	0.50
D1	2.90	3.05	3.20	L1	0.13 REF		
D2	1.45	1.70	1.95	K	0.30 REF		
D3	0.13 REF			θ	0°	12°	
E	3.05	3.25	3.40	M	0.15 REF		
E1	2.90	3.10	3.25				